TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74HC590AP,TC74HC590AF

#### 8-Bit Binary Counter/Register with 3-State Outputs

The TC74HC590A is a high speed CMOS 8-BIT COUNTER/REGISTER fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to epuivalent LSTTL while maintaining the CMOS low power dissipation.

The internal counter counts on the positive going edge of Counter Clock (CCK) when Counter Clock Enable ( $\overline{\text{CCKEN}}$ ) is low. When Counter Clear ( $\overline{\text{CCLR}}$ ) is low, the internal counter is cleared asynchronously to the clock.

Data in the internal counter are loaded into the register at positive going edge of Register Clock (RCK), and the register outputs are controlled by enable input ( $\overline{G}$ ).

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

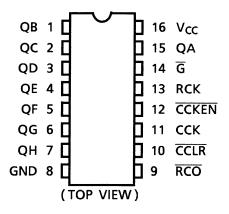
#### **Features**

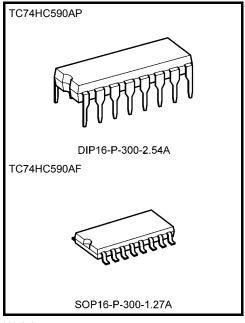
- High speed:  $f_{max} = 62 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 4 \mu A \text{ (max)}$  at  $T_{a} = 25 \text{°C}$
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- Output drive capability: 15 LSTTL loads for QA to QH 10 LSTTL loads for  $\overline{\text{RCO}}$
- Symmetrical output impedance: | I<sub>OH</sub> | = I<sub>OL</sub> = 6 mA (min)

For QA to QH  $|I_{OH}| = I_{OL} = 4 \text{ mA (min)}$  For  $\overline{RCO}$ 

- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range: VCC (opr) = 2 to 6 V
- Pin and function compatible with 74LS590

#### Pin Assignment

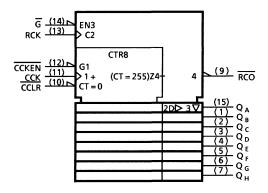




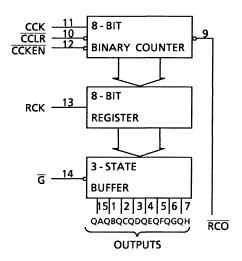
Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.)

## **IEC Logic Symbol**



## **Block Diagram**



#### **Truth Table**

		Inputs			Function
G	RCK	CCLR	CCKEN	ССК	Function
Н	Х	Х	Х	Х	Q Outputs Disable
L	Х	Х	Х	Х	Q Outputs Enable
Х		Х	Х	Х	Counter Data is Stored into Register
Х	$\downarrow$	Х	Х	Х	Register State is not Changed
Х	Х	L	Х	Х	Counter Clear
Х	Х	Н	L		Advance One Count
Х	Х	Н	L		No Count
Х	Х	Н	Н	Х	No Count

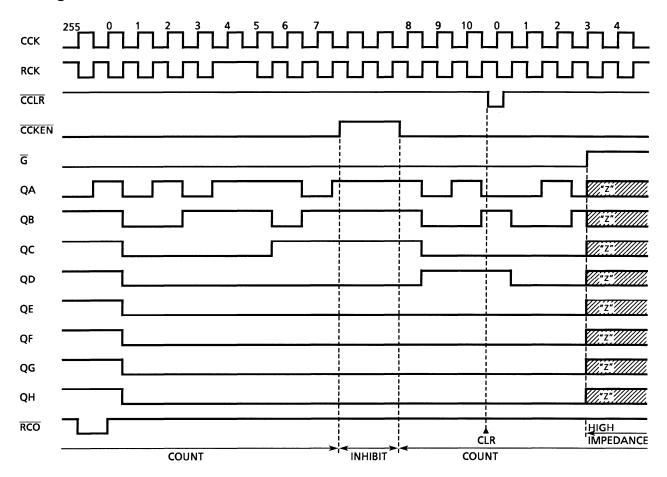
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X: Don't care

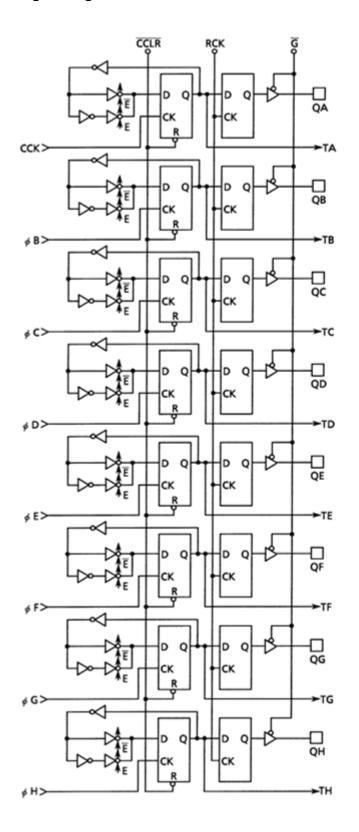
 $\overline{RCO} = \overline{QA' \cdot QB' \cdot QC' \cdot QD' \cdot QE' \cdot QF' \cdot QG' \cdot QH'}$ 

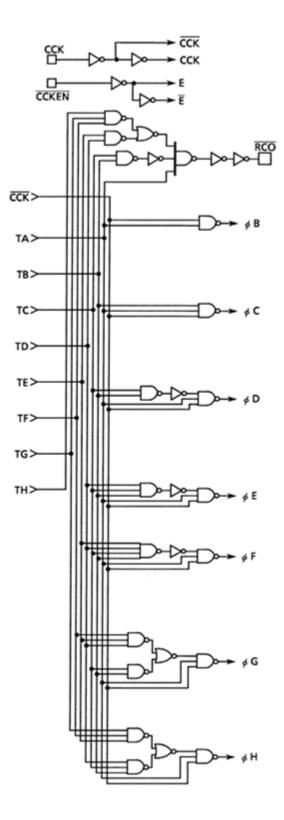
(QA' to QH': internal outputs of the counter)

## **Timing Chart**



## **Logic Diagram**





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#### **Absolute Maximum Ratings (Note 1)**

Characteristic	cs	Symbol	Rating	Unit	
Supply voltage range		$V_{CC}$	–0.5 to 7	V	
DC input voltage		$V_{IN}$	−0.5 to V <sub>CC</sub> + 0.5	V	
DC output voltage		V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> + 0.5	V	
Input diode current		I <sub>IK</sub>	±20	mA	
Output diode current		lok	±20	mA	
DC output current	(RCO)	lour	±25	mA	
DC output current	(QA to QH)	lout	±35		
DC V <sub>CC</sub> /ground current		Icc	±75	mA	
Power dissipation		$P_{D}$	500 (DIP) (Note 2)/180 (SOP)	mW	
Storage temperature		T <sub>stg</sub>	-65 to 150	°C	

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to  $65^{\circ}C$ . From Ta = 65 to  $85^{\circ}C$  a derating factor of -10 mW/°C shall be applied until 300 mW.

## **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2 to 6	V
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	<b>V</b>
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	>
Operating temperature	T <sub>opr</sub>	−40 to 85	°C
		0 to 1000 (V <sub>CC</sub> = 2.0 V)	
Input rise and fall time	t <sub>r</sub> , t <sub>f</sub>	0 to 500 (V <sub>CC</sub> = 4.5 V)	ns
		0 to 400 (V <sub>CC</sub> = 6.0 V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{CC}$  or GND.

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## **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	Symbol	Test Condition			-	Га = 25°C		Ta = -40 to 85°C		- Unit	
Characteristics	Cymbol				V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Onit
					2.0	1.50	_	_	1.50	_	
High-level input voltage	$V_{IH}$			_	4.5	3.15	_	_	3.15	_	V
					6.0	4.20	_	_	4.20	_	
					2.0	_	_	0.50	_	0.50	
Low-level input voltage	$V_{IL}$			_	4.5	_	_	1.35	_	1.35	V
					6.0	_	_	1.80	_	1.80	
		.,			2.0	1.9	2.0	_	1.9	_	
		V <sub>IN</sub> = V <sub>IH</sub>	or V <sub>IL</sub>	$I_{OH} = -20 \mu A$	4.5	4.4	4.5	_	4.4	_	
	V <sub>ОН</sub>	"'			6.0	5.9	6.0	_	5.9	_	
High-level output voltage			RCO	$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	V
			ROO	$I_{OH} = -5.2 \text{ mA}$	6.0	5.68	5.80	_	5.63	_	
			QA to	$I_{OH} = -6 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	
			QH	$I_{OH} = -7.8 \text{ mA}$	6.0	5.68	5.80	_	5.63	_	
	V <sub>OL</sub>	.,			2.0	_	0.0	0.1	_	0.1	
		V <sub>IN</sub> = V <sub>IH</sub>	or V <sub>IL</sub>	$I_{OL} = 20 \ \mu A$	4.5	_	0.0	0.1	_	0.1	
					6.0	_	0.0	0.1	_	0.1	
Low-level output voltage			RCO	I <sub>OL</sub> = 4 mA	4.5	_	0.17	0.26		0.33	V
			ROO	I <sub>OL</sub> = 5.2 mA	6.0	_	0.18	0.26	_	0.33	
			QA to	I <sub>OL</sub> = 6 mA	4.5	_	0.17	0.26	_	0.33	
			QH	$I_{OL} = 7.8 \text{ mA}$	6.0	_	0.18	0.26	_	0.33	
3-state output off-state current	I <sub>OZ</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND		6.0	_	_	±0.5	_	±5.0	μА	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND			6.0			±0.1		±1.0	μА
Quiescent supply current	Icc	V <sub>IN</sub> =	V <sub>CC</sub> or G	ND	6.0	_	_	4.0	_	40.0	μА



## Timing Requirements (input: $t_r = t_f = 6$ ns)

Characteristics	Symbol		Ta = 25°C		Ta = -40 to 85°C	Unit	
			V <sub>CC</sub> (V)	Тур.	Limit	Limit	
Minimum pulse width	tu an		2.0	_	75	95	
(CCK, RCK)	tw (H)	_	4.5	_	15	19	ns
(OOK, NOK)	t <sub>W (L)</sub>		6.0	_	13	16	
Minimum pulse width			2.0	_	75	95	
(CCLR)	t <sub>W (L)</sub>	_	4.5	_	15	19	ns
(COLK)			6.0	_	13	16	
Minimum set-up time			2.0	_	100	125	
(CCKEN-CCK)	ts	_	4.5	_	20	25	ns
(CORLIN-COR)			6.0	_	17	21	
Minimum set-up time			2.0	_	200	250	
(CCK-RCK)	ts	_	4.5	_	40	50	ns
(CCK-RCK)			6.0	_	34	43	
			2.0	_	0	0	
Minimum hold time	t <sub>h</sub>	_	4.5	_	0	0	ns
			6.0	_	0	0	
Minimum removal time			2.0	_	75	95	
(CCLR)	t <sub>rem</sub>	_	4.5	_	15	19	ns
(COLN)			6.0	_	13	16	
			2.0	_	6	5	
Clock frequency	f	_	4.5	_	33	26	MHz
			6.0	_	39	31	

# AC Characteristics (C<sub>L</sub> = 15 pF, $V_{CC}$ = 5 V, Ta = 25°C, input: $t_r$ = $t_f$ = 6 ns)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time ( RCO )	t <sub>TLH</sub> t <sub>THL</sub>	_	_	4	8	ns
Propagation delay time (CCK- RCO)	t <sub>pLH</sub>	_	_	18	28	ns
Propagation delay time ( CCLR - RCO )	t <sub>pLH</sub>	_	_	20	30	ns
Maximum clock frequency	f <sub>max</sub>	_	32	62	_	MHz



AC Characteristics (input:  $t_r = t_f = 6$  ns)

Characteristics	Symbol	Test Condition			-	Γa = 25°0		Ta –40 to	Unit	
Characteristics	Symbol		CL (pF)	V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Offic
Output transition time (Qn)	t <sub>TLH</sub>	_	50	2.0 4.5	_ _	25 7	60 12	_ _	75 15	ns
(QII)	tTHL			6.0	_	6	10	_	13	
Output transition time	t <sub>TLH</sub>			2.0	_	30	75	_	95	
(RCO)	t <sub>THL</sub>	_	50	4.5	_	8	15	_	19	ns
,	1112			6.0		7	13	_	16	
Propagation delay	$t_{pLH}$			2.0	_	75	163	_	205	
time (CCK- RCO)	t <sub>pHL</sub>	_	50	4.5	_	22	33	_	41	ns
(CCK-RCO)	<b>F</b>			6.0	_	17	28	_	35	
Propagation delay				2.0	_	78	175	_	220	
time ( CCLR - RCO )	t <sub>pLH</sub>	_	50	4.5	_	23	35	_	44	ns
(CCLR - RCO)				6.0		18	30		37	
				2.0	_	62	145	_	180	
Propagation delay			50	4.5	_	19	29	_	36	
time	t <sub>pLH</sub>	_		6.0	_	15	25	_	31	ns
(RCK-Qn)	t <sub>pHL</sub>			2.0	_	78	185	_	230	
			150	4.5	_	24	37	_	46	
				6.0		19	31		39	
				2.0	_	43	105	_	130	
			50	4.5	_	14	21	_	26	
Output enable time	$t_{pZL}$	$R_L = 1 \text{ k}\Omega$		6.0	_	12	18	_	22	ns
	<sup>t</sup> pZH			2.0	_	58	150	_	190	
			150	4.5		19	30		38	
				6.0	_	16	26	_	33	
	$t_{pLZ}$			2.0	_	33	105	_	130	
Output disable time	t <sub>pHZ</sub>	$R_L = 1 \text{ k}\Omega$	50	4.5	_	16	21	_	26	ns
	'			6.0	_	12	18	_	22	
Maximum clock	_			2.0	6	12	_	5	_	
frequency	f <sub>max</sub>	_	50	4.5	30	51	_	24	_	MHz
Input capacitance	C <sub>IN</sub>			6.0	35	80 5	10	28 —	10	pF
		_				3	10		10	ρι
Power dissipation capacitance	C <sub>PD</sub> (Note)	_			_	34	_	_	_	pF

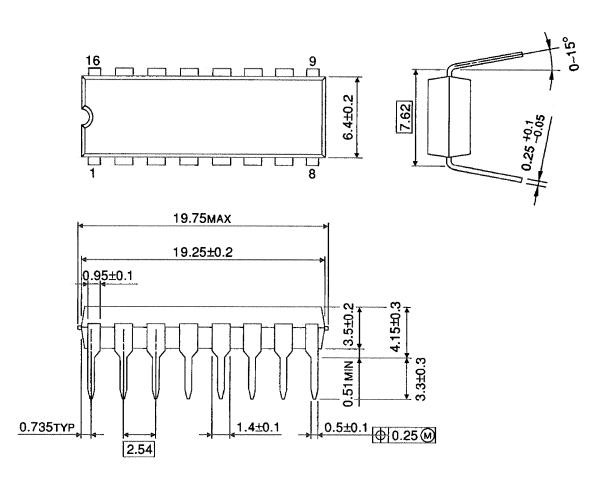
Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}$$
 (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

## **Package Dimensions**

DIP16-P-300-2.54A Unit: mm

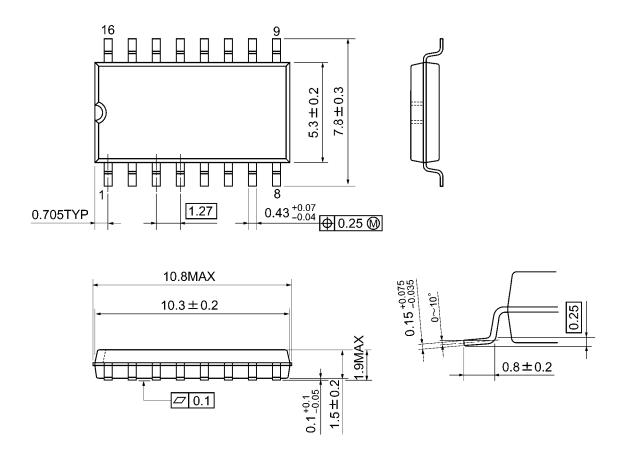


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Weight: 1.00 g (typ.)

## **Package Dimensions**

SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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